

Notice of References Cited	Application/Control No. 10/043,696		Applicant(s)/Patent Under Reexamination ZELEK ET AL.	
	Examiner Linda Krisciunas		Art Unit 3623	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,287,284	02-1994	Sugino et al.	700/97
*	B	US-6,704,015	03-2004	Bovarnick et al.	345/440.2
*	C	US-5,581,466	12-1996	Van Wyk et al.	700/95
*	D	US-5,999,908	12-1999	Abelow, Daniel H.	705/1
*	E	US-5,963,953	10-1999	Cram et al.	707/102
*	F	US-5,765,137	06-1998	Lee, Don Joon	705/7
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	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Quantifying design and manufacturing robustness through stochastic optimization techniques" by Kazmer et al, Proceedings of the 1996 ASME Design Engineering Technical Conferences and Computers in Engineering Conference, August 1996.
	V	"The identification and use of key characteristics in the product development process" by Lee et al, Proceedings of the 1996 ASME Design Engineering Technical Conferences and Computers in Engineering Conference, August 1996.
	W	"CADET: A software support tool for constraint processes in embodiment design" by Thornton et al, Research in Engineering Design, Publisher: Springer-Verlag, 1996.
	X	"Modeling, Optimization and control of spatial uniformity in manufacturing processes" by Guo et al, IEEE, February 1993.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.